

Abstracts

Contactless probing of high-frequency electrical signals with scanning probe microscopy

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Circuit internal test techniques working in a contactless manner are necessary for failure analysis and design verification of high-speed and high-frequency circuits. A relative new technique is the scanning probe voltage measurement technique, a technique which is based on scanning probe microscopy. This paper gives an overview of the state-of-the-art of this technique and demonstrates some practical examples.

 [Return to main document.](#)